



SEMI® International Standards Program

Compound Semiconductor Technical Committee Meeting

Virtual Meeting

Thursday 29th July 2021
16:30-18:30 CEST / 7:30-9:30am PDT

V2 31.05.2021

Co-chairs:

- Dr. Arnd-Dietrich Weber, SiCrystal
- N.N.

Agenda

European Compound Semiconductor Committee Meeting (Virtual Meeting)

16:30	Welcome and Self-Introductions	all
16:35	SEMI Standards Overview and Legal Reminders	SEMI Staff
16:40	Review of the minutes and action items from the previous meeting	SEMI Staff
16:45	Task Force Reports (~5 minutes each) • XRT Test Method for SiC Task Force • 5-year Review (M46, M63, M75) Task Force • SiC-Task Force	C. Kranert H. Alt A. Weber
17:00	Ballot Review for: • Doc. 6779 Reapproval of SEMI M64-0915 Test Method For The EI2 Deep Donor Concentration In Semi-Insulating (Si) Gallium Arsenide Single Crystals By Infrared Absorption Spectroscopy – H. Alt • Doc. 6780 Line Item Revision of SEMI M87-0116 Test Method For Contactless Resistivity Measurement Of Semi-Insulating Semiconductors – H. Alt	
17:45	New Business: • (open discussion)	N.N.
18:00	Compound Materials Liaison Reports • North America • Japan • China	SEMI Staff
18:15	Any Other Business / Questions	A. Weber
18:25	Next Meetings	
18:30	End	